Search Notes

Application/Control No.			Applicant(s)/Patent under Reexamination	
10/535,7	08	TAKEHIRO M	IORIYA ET AL	
Examiner		Art Unit		
LAM T. N	1AI	2819		

	SEAR	CHED	
Class	Subclass	Date	Examiner
341	50,82	4/17/2006	LM
€ 375	100-136	4/17/2006	LM

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
9				
East Text search	4/17/2006	LM		
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